

Notice of References Cited	Application/Control No. 10/648,541		Applicant(s)/Patent Under Reexamination OKAMOTO ET AL.	
	Examiner Jeffrie R. Lund		Art Unit 1763	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,989,637	02-1991	Dittrich, Hans	137/599.03
*	B	US-5,516,366	05-1996	Kanno et al.	118/715
*	C	US-5,653,807	08-1997	Crumbaker, Todd E.	118/715
*	D	US-6,074,487	06-2000	Yoshioka et al.	118/726
*	E	US-6,110,531	08-2000	Paz de Araujo et al.	427/255.25
*	F	US-6,440,495 B1	08-2002	Wade et al.	427/250
*	G	US-6,443,435 B1	09-2002	Hendrickson, Scott	261/128
*	H	US-6,464,782 B1	10-2002	Sivaramakrishnam et al.	117/202
*	I	US-2002/0001674 A1	01-2002	UHLENBROCK, STEFAN	427/248.1
*	J	US-2004/0187777 A1	09-2004	Okamoto et al.	118/715
*	K	US-2005/0045099 A1	03-2005	Bencher et al.	118/715
*	L	US-2005/0106763 A1	05-2005	Hsieh et al.	438/005
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.